

U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-10685-1P US		09/778,245	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant(s)			
(See several sheets if necessary)					SHING LEE ET AL.			
					Filing Date		Group	
					February 6, 2001		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HP	AA	5,042,951	8/91	Gold et al.			
HP	AB	5,166,752	11/92	Spanier et al.			
HP	AC	5,181,080	1/93	Fantom et al.			
HP	AD	5,486,701	1/96	Norton et al.			
HP	AE	5,596,406	1/97	Rosencwaig et al.			
HP	AF	5,608,526	3/97	Piwonka-Corle et al.			
HP	AG	5,747,813	5/98	Norton et al.			
HP	AH	5,910,842	6/99	Piwonka-Corle et al.			
HP	AI	6,184,984	2/01	Lee et al.			

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
HP	AI	"Analysis of Semiconductor Surfaces With Very Thin Native Oxide Layers By Combined Immersion And Multiple Angle Of Incidence Ellipsometry," I. Ohlidal et al., <i>Applied Surface Science</i> , 35 (1988-89), pp. 259-273						
HP	AJ	"Determination of the "Optical" Thickness And Of The Filling Factor Of Discontinuous Au Films From Photometric And Ellipsometric Measurements," E. Elizalde et al., <i>Optics Communications</i> , Vol. 60, No. 6, December 15, 1986, pp. 378-382						
HP	AK	"Variable Angle Spectroscopic Ellipsometry," S.A. Alterovitz et al., <i>Solid State Technology</i> , March 1988						
HP	AL	"Application of spectroscopic ellipsometry to complex samples," J.L. Freeouf, <i>Appl. Phys. Lett.</i> , 53(24), December 12, 1988, pp. 2426-2428						
HP	AM	"Spectroscopic ellipsometry studies of SIMOX structures and correlation with cross-section TEM," <i>Vacuum</i> , Vol. 42, Nos. 5/6, 1991, pp. 359-365						
HP	AN	"Spectroscopic Ellipsometry for the Characterization of Thin Films," F. Ferrieu et al. <i>J. Electrochem. Soc.</i> , 137, No. 7, July 1990, pp. 2203-2208						
HP	AO	International Search Report dated 6/8/2000						

Examiner	<i>H. Raw</i>	Date Considered	1/23/02
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*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.